

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10632823	VENKATACHALAM, VIDYA
	Examiner	Art Unit
	Bloom, Nathan	2609

SEARCHED

Class	Subclass	Date	Examiner
382	150,155-161		

SEARCH NOTES

Search Notes	Date	Examiner
Inventor and Assignee Search	2/06/07	
East Keyword Search	2/08/07	
IEEE Search: Inspection Systems using a Hough or Radon transform and Neural Networks	2/13/2007	
ACM and SPIE Search: Inspection systems using a Hough or Radon transform and Neural Networks	2/14/2007	
Consulted Samir Ahmed	2/15/2007	
Consulted Tommy Chin regarding 101 rejection	2/15/2007	

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner